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# **ALD of Manganese Silicate**

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## **Outline**

Potential Applications of Manganese Silicate ALD Process for Manganese Oxide, MnO ALD Process for Manganese Silicate

**Properties of Manganese Silicate** 



# Potential Applications of MnSi<sub>x</sub>O<sub>v</sub>

Copper wires in computer chips could use MnSi<sub>x</sub>O<sub>v</sub> as a

barrier to diffusion of copper, water and oxygen
adhesion promoter between copper and insulators
nucleating layer for vapor deposition of copper

#### Manganese Precursors



melting point: 60 °C boiling point: 120 °C / 0.02 torr





manganese(II) bis(*N*,*N*'-di-*tert*-butylacetamidinate)

melting point: 107 °C boiling point: 100 °C/ 0.07 torr



# **Saturation Curve for Manganese Oxide** Saturated for doses > 10<sup>-5</sup> moles/cycle



### **Saturation Curve for Manganese Oxide** Saturated for doses > 10<sup>-5</sup> moles/cycle



# Thickness per Cycle for Manganese Oxide nearly constant from 200 to 340 °C



### **Rutherford Backscattering Spectroscopy** => Stoichiometry MnO Adding O<sub>2</sub> cycles => MnO<sub>2</sub>



# X-Ray Photoelectron Spectroscopy < 1% C or N impurities



#### **XRD shows polycrystalline MnO**



#### **Precursors for Silicon and Oxygen**



tris-*tert*-butoxysilanol (TBS)

melting point: 63 - 65 °C boiling point: 205 - 210 °C/ 760 torr



tris-tert-pentoxysilanol (TPS)

melting point: < 20 °C boiling point: 96-99 °C/ 2-3 torr

## **ALD Conditions for Manganese Silicate**

Substrate: SiO<sub>2</sub>/Si UV ozone cleaning: 2 min Drying at 350°C: 1 hour

Mn amidinate source =105°C Si/O source (TPS)=120°C

T(substrate)= 350°C

Cycle times (s): 1/30/4/30 (Mn(amd)/purge/TPS/purge)

growth per cycle = 0.43 nm



High growth per cycle due to a catalytic mechanism similar to that of aluminum-catalyzed silica: Dennis Hausmann, Jill Becker, Shenglong Wang, Roy G. Gordon, Science 298, 402 (2002)

# Saturation Curve for MnSi<sub>x</sub>O<sub>y</sub> vs. Silicate Precursor





# **STEM EDX Mapping of Elements**



#### **Composition by Rutherford Backscattering Spectroscopy**

Cycles	Mn 10 <sup>15</sup> at/cm^2	Si 10 <sup>15</sup> at/cm^2	O 10 <sup>15</sup> at/cm^2	Mn:Si:O
10	2.32	6.2	24	1 : 2.7 : 10
20	5.56	15	47	1 : 2.7 : 8
50	15.4	41	117	1 : 2.7 : 7.6

Stoichiometry ~  $MnSi_{2.7}O_{7.6}$  so Mn is oxidized to  $Mn^{4+}$ 

#### **Cu diffusion test**

anneal samples in  $N_2$  for 1h at 450 C, use Ni etchant to remove Cu film, then EDX



#### CV tests after electric field at room temperature





#### Effectiveness of MnSi<sub>x</sub>O<sub>y</sub> as a Cu Diffusion Barrier

Composition	Structure	Cu Barrier	Diffusion Pathway
SiO <sub>2</sub>	amorphous	no	open tetrahedral network
MnSi <sub>2.7</sub> O <sub>7.6</sub>	amorphous	yes	paths blocked by Mn ions
MnO	polycrystalline	no	grain boundaries

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